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INTERNATIONAL STANDARD

QC 300000

**Fixed capacitors for use in electronic equipment –
Part 1: Generic specification**

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ELECTROTECHNICAL
COMMISSION

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CONTENTS

FOREWORD.....	7
1 General.....	9
1.1 Scope.....	9
1.2 Normative references.....	9
2 Technical data.....	10
2.1 Units and symbols.....	10
2.2 Terms and definitions.....	11
2.3 Preferred values.....	17
2.3.1 General.....	17
2.3.2 Preferred values of nominal capacitance.....	17
2.3.3 Preferred values of rated voltage.....	17
2.4 Marking.....	17
2.4.1 General.....	17
2.4.2 Coding.....	17
3 Quality assessment procedures.....	17
4 Tests and measurement procedures.....	18
4.1 General.....	19
4.2 Standard atmospheric conditions.....	19
4.2.1 Standard atmospheric conditions for testing.....	19
4.2.2 Recovery conditions.....	19
4.2.3 Referee conditions.....	20
4.2.4 Reference conditions.....	20
4.3 Drying.....	20
4.4 Visual examination and check of dimensions.....	20
4.4.1 Visual examination.....	20
4.4.2 Dimensions (gauging).....	20
4.4.3 Dimensions (detail).....	20
4.5 Insulation resistance.....	21
4.5.1 Preconditioning.....	21
4.5.2 Measuring conditions.....	21
4.5.3 Test points.....	21
4.5.4 Test methods.....	21
4.5.5 Temperature compensation.....	22
4.5.6 The relevant specification shall prescribe:.....	22
4.6 Voltage proof.....	23
4.6.1 Test circuit (for the test between terminations).....	23
4.6.2 Test.....	24
4.6.3 Requirements.....	26
4.6.4 Conditions to be prescribed in the relevant specification.....	26
4.7 Capacitance.....	26
4.7.1 Measuring frequency and measuring voltage.....	26
4.7.2 Measuring equipment.....	26
4.7.3 Conditions to be prescribed in the relevant specification.....	26
4.8 Tangent of loss angle and equivalent series resistance (ESR).....	27
4.8.1 Tangent of loss angle.....	27
4.8.2 Equivalent series resistance (ESR).....	27

4.9	Leakage current	27
4.9.1	Preconditioning.....	27
4.9.2	Test method	28
4.9.3	Power source	28
4.9.4	Measuring accuracy.....	28
4.9.5	Test circuit	28
4.9.6	Conditions to be prescribed in the relevant specification.....	28
4.10	Impedance	28
4.11	Self-resonant frequency and inductance.....	29
4.11.1	Self-resonant frequency (f_r)	29
4.11.2	Inductance.....	32
4.11.3	Conditions to be prescribed in the relevant specification.....	32
4.12	Outer foil termination.....	32
4.13	Robustness of terminations	33
4.13.1	Test Ua ₁ – Tensile.....	33
4.13.2	Test Ub – Bending (half of the sample).....	33
4.13.3	Test Uc – Torsion (remaining sample)	33
4.13.4	Test Ud – Torque (for terminations with threaded studs or screws and for integral mounting devices).....	33
4.13.5	Visual examination	34
4.14	Resistance to soldering heat	34
4.14.1	Preconditioning.....	34
4.14.2	Test procedure	34
4.14.3	Recovery.....	34
4.14.4	Final inspection, measurement and requirements	34
4.15	Solderability	34
4.15.1	Preconditioning.....	34
4.15.2	Test procedure	35
4.15.3	Final inspection, measurements and requirements	35
4.16	Rapid change of temperature	35
4.16.1	Initial measurement	35
4.16.2	Test procedure	35
4.16.3	Final inspection, measurements and requirements	35
4.17	Vibration.....	36
4.17.1	Initial measurement	36
4.17.2	Test procedure	36
4.17.3	Electrical test.....	36
4.17.4	Final inspection, measurements and requirements	36
4.18	Bump	36
4.18.1	Initial measurement	36
4.18.2	Test procedure	36
4.18.3	Final inspection, measurements and requirements	36
4.19	Shock.....	36
4.19.1	Initial measurement	36
4.19.2	Test procedure	36
4.19.3	Final inspection, measurements and requirements	37
4.20	Container sealing	37
4.21	Climatic sequence.....	37
4.21.1	Initial measurements	37

4.21.2	Dry heat	37
4.21.3	Damp heat, cyclic, test Db, first cycle	37
4.21.4	Cold	37
4.21.5	Low air pressure	38
4.21.6	Damp heat, cyclic, test Db, remaining cycles	38
4.21.7	Final measurements	38
4.22	Damp heat, steady state	38
4.22.1	Initial measurement	38
4.22.2	Test procedure	38
4.22.3	Final inspection, measurements and requirements	39
4.23	Endurance	39
4.23.1	Initial measurements	39
4.23.2	Test procedure	39
4.23.3	Conditions to be prescribed in the relevant specification	39
4.23.4	Test voltage	39
4.23.5	Placement in the test chamber	40
4.23.6	Recovery	40
4.23.7	Final inspection, measurements and requirements	40
4.24	Variation of capacitance with temperature	41
4.24.1	Static method	41
4.24.2	Dynamic method	41
4.24.3	Methods of calculation	42
4.25	Storage	43
4.25.1	Storage at high temperature	43
4.25.2	Storage at low temperature	43
4.26	Surge	43
4.26.1	Initial measurement	43
4.26.2	Test procedure	43
4.26.3	Final inspection, measurements and requirements	45
4.26.4	Information to be given in the relevant detail specification	45
4.27	Charge and discharge tests and inrush current test	45
4.27.1	Initial measurement	45
4.27.2	Test procedure	45
4.27.3	Charge and discharge	47
4.27.4	Inrush current	47
4.27.5	Final inspection, measurements and requirements	47
4.28	Pressure relief (for aluminium electrolytic capacitors)	47
4.28.1	a.c. test	47
4.28.2	d.c. test	47
4.28.3	Pneumatic test	47
4.28.4	Final inspection, measurements and requirements	48
4.29	Characteristics at high and low temperature	48
4.29.1	Test procedure	48
4.29.2	Requirements	48
4.30	Thermal stability test	48
4.31	Component solvent resistance	48
4.31.1	Initial measurements	48
4.31.2	Test procedure	48
4.31.3	Final inspection, measurements and requirements	49

4.32	Solvent resistance of marking.....	49
4.32.1	Test procedure	49
4.32.2	Final inspection, measurements and requirements	49
4.33	Mounting (for surface mount capacitors only)	49
4.33.1	Substrate.....	49
4.34	Shear test	52
4.34.1	Test procedure	52
4.34.2	Final inspection, measurements and requirements	52
4.35	Substrate bending test	52
4.35.1	Test procedure	52
4.35.2	Recovery	52
4.35.3	Final inspection and requirements	52
4.36	Dielectric absorption.....	52
4.36.1	Test procedure	52
4.36.2	Requirement.....	53
4.37	Accelerated damp heat, steady state (for multilayer ceramic capacitors only).....	53
4.37.1	Mounting of capacitors	53
4.37.2	Initial measurement	53
4.37.3	Test procedure	53
4.37.4	Recovery	54
4.37.5	Final inspection, measurements and requirements	54
4.38	Passive flammability.....	54
4.38.1	Test procedure	54
4.38.2	Final inspection, measurements and requirements	54
4.39	High surge current test.....	55
4.39.1	Initial measurements	55
4.39.2	Test procedure	55
4.39.3	Requirements for the charging circuit	55
4.39.4	Nonconforming items.....	56
4.40	Voltage transient overload (for aluminium electrolytic capacitors with non-solid electrolyte).....	56
4.40.1	Initial measurement	56
4.40.2	Test procedure	56
4.40.3	Final inspection, measurements and requirements	57
4.40.4	Conditions to be prescribed in the relevant specification.....	57
Annex A (normative) Interpretation of sampling plans and procedures as described in IEC 60410 for use within the IECQ system.....		58
Annex B (normative) Rules for the preparation of detail specifications for capacitors and resistors for electronic equipment for use within the IECQ system.....		59
Annex C (normative) Layout of the first page of a PCP/CQC specification.....		60
Annex D (normative) Requirements for capability approval test report		61
Annex E (informative) Guide for pulse testing of capacitors		62
Annex F (informative) Guidance for the extension of endurance tests on fixed capacitors.....		65
Annex G (normative) Damp heat, steady state with voltage applied, for metallized film capacitors only		66
Annex Q (normative) Quality assessment procedures		67
Figure 1 – Reactive power against frequency.....		13

Figure 2 – Relation between category temperature range and applied voltage	16
Figure 3 – Voltage-proof test circuit	24
Figure 4 – Schematic diagram of the impedance measuring circuit	28
Figure 5 – Capacitor mounting arrangement	30
Figure 6 – Capacitor mounting arrangement	30
Figure 7 – Typical diagram of an absorption oscillator-wavemeter	31
Figure 8 – Schematic diagram of the measuring circuit	31
Figure 9 – Test circuit	32
Figure 10 – Test circuit for electrolytic capacitors	40
Figure 11 – Relay circuit	44
Figure 12 – Thyristor circuit	44
Figure 13 – Voltage waveform across capacitor	45
Figure 14 – Voltage and current waveform	46
Figure 15 – Suitable substrate for mechanical tests (may not be suitable for impedance measurements)	51
Figure 16 – Suitable substrate for electrical tests	51
Figure 17 – High surge current test	55
Figure 18 – Voltage transient overload test circuit	56
Figure 19 – Voltage waveform	57
Figure Q.1 – General scheme for capability approval	70
Table 1 – Referee conditions	20
Table 2 – Measurement of insulation resistance	21
Table 3 – Measuring points	23
Table 4 – Tensile force	33
Table 5 – Torque	33
Table 6 – Number of cycles	38
Table 7 – Severities and requirements	54

INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –**Part 1: Generic specification**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 60384-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment

This fourth edition cancels and replaces the third edition issued in 1999 and constitutes a technical revision, including minor revisions related to tables, figures and references.

This edition contains the following significant technical changes with respect to the previous edition:

- implementation of Annex Q which replaces Clause 3.

The text of this standard is based on the following documents:

FDIS	Report on voting
40/1915/FDIS	40/1924/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

The QC number that appears on the front cover of this publication is the specification number in the IECQ Quality Assessment System for Electronic Components (IECQ).

A list of all the parts of the IEC 60384 series, under the general title *Fixed capacitors for use in electronic equipment*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later stage.

The contents of the corrigendum of November 2008 have been included in this copy.

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –

Part 1: Generic specification

1 General

1.1 Scope

This part of IEC 60384 is a generic specification and is applicable to fixed capacitors for use in electronic equipment.

It establishes standard terms, inspection procedures and methods of test for use in sectional and detail specifications of electronic components for quality assessment or any other purpose.

1.2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027, *Letter symbols to be used in electrical technology*

IEC 60050 (all parts), *International Electrotechnical Vocabulary (IEV)*

IEC 60062, *Marking codes for resistors and capacitors*

IEC 60063, *Preferred number series for resistors and capacitors*

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-1:2007, *Environmental testing – Part 2-1: Tests – Tests A: Cold*

IEC 60068-2-2:2007, *Environmental testing – Part 2-2: Tests – Tests B: Dry heat*

IEC 60068-2-6:2007, *Environmental testing – Part 2: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-13:1983, *Environmental testing – Part 2: Tests – Test M: Low air pressure*

IEC 60068-2-14:1984, *Environmental testing – Part 2: Tests – Test N: Change of temperature*

IEC 60068-2-17:1994, *Environmental testing – Part 2-17: Tests – Test Q: Sealing*

IEC 60068-2-20:1979, *Environmental testing – Part 2-20: Tests – Test T: Soldering*

IEC 60068-2-21:2006, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27:2008, *Environmental testing – Part 2-27: Tests – Test Ea and guidance: Shock*

IEC 60068-2-29:1987, *Environmental testing – Part 2-29: Tests – Test Eb and guidance: Bump*

IEC 60068-2-30:2005, *Environmental testing – Part 2-30: Tests – Test Db: Damp heat, cyclic (12 h + 12 h cycle)*

IEC 60068-2-45:1980, *Environmental testing – Part 2-45: Tests – Test XA and guidance: Immersion in cleaning solvents*

IEC 60068-2-54:2006, *Environmental testing – Part 2-54: Tests – Test Ta: Solderability testing of electronic components by the wetting balance method*

IEC 60068-2-58:2004, *Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-69:2007, *Environmental testing – Part 2: Tests – Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method*

IEC 60068-2-78:2001, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state*

IEC 60294, *Measurement of the dimensions of a cylindrical component having two axial terminations*

IEC 60410:1973, *Sampling plans and procedures for inspection by attributes*

IEC 60617, *Graphical symbols for diagrams*

IEC 60695-11-5:2004, *Fire hazard testing – Part 11-5: Test flames – Needle-flame test method – Apparatus, confirmatory test arrangement and guidance*

IEC 60717, *Method for the determination of the space required by capacitors and resistors with unidirectional terminations*

IEC 61193-2, *Quality assessment systems – Part 2: Selection and use of sampling plans for inspection of electronic components and packaging¹*

IEC 61249-2-7:2002, *Materials for printed boards and other interconnecting structures – Part 2-7: Reinforced base materials clad and unclad – Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad*

IEC QC 001002-3, *Rules of Procedure – Part 3: Approval procedures*

ISO 3, *Preferred numbers – Series of preferred numbers*

ISO 1000, *SI units and recommendations for the use of their multiples and of certain other units*

ISO 9000, *Quality management systems – Fundamentals and vocabulary*

¹ To be published.